#### Cassini Basic Training Seminar



#### **Developing and Running Test Plans**



## Cassini Basic Seminar Outline

- Operation and Troubleshooting
- System Administration and Maintenance
- Developing and Running RI Test Plans
- Science of RF Measurement
- Device Definitions
- Example Applications Development
- Test Fixture and Device Interface Design
- Test Design & Best Practices Test Optimization
- Application User Guides

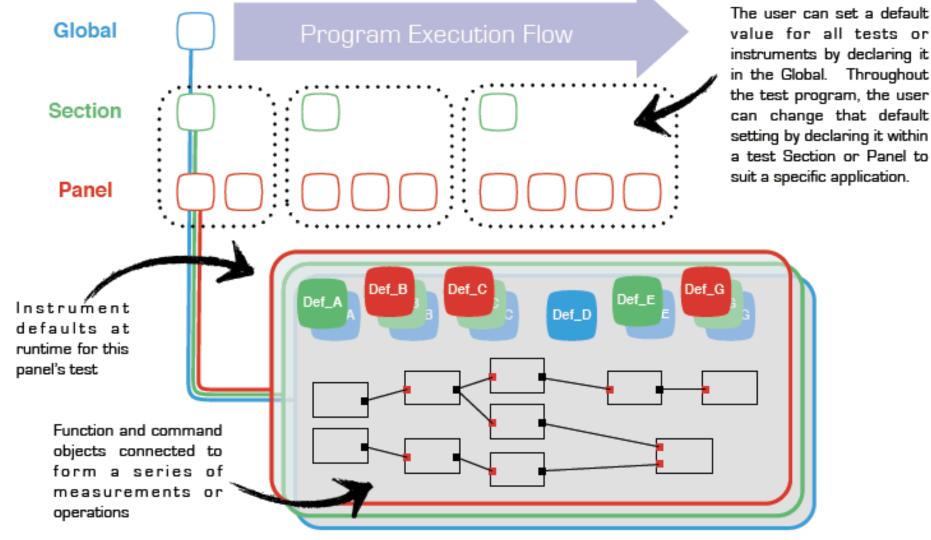
# Chapter Outline (Ch 3)

- Creating a New Test Plan
- Understanding Test Plan Structure
- Building a Test Plan
- Saving Data
- Editing the Tester Configuration
- Compiling & Running Test Plan
- Viewing Test Results
- Setting Limits
- Release Test Plan for Production

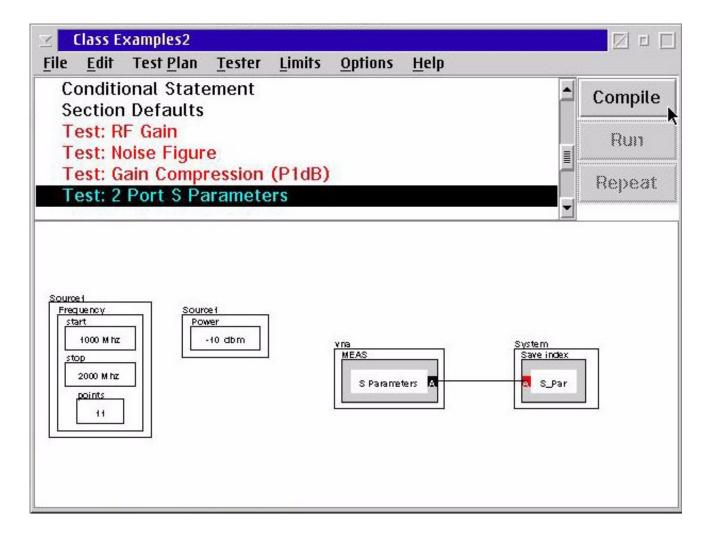
#### **Test Plan Concepts**

- States
- Measurements
- Limits
- Inheritance global defaults, section defaults
- Buttons (objects)
- Run time vs. Design time

**Test Plan Structure** 



# Typical Test Plan



# **Creating Test Plan**

- Creating a New Test Plan
- Change the Device Type
- Change the Interface Board
- Change the Fixture
- Edit the new Test Plan

#### **Creating a New Test Plan**

- From the RI Message Window, select **Test** and **Plans...**
- From the Select Testplan window, select New

	Select Testplan
	Type Device
9	-all-
RI Cassini GF10RC2A 18-	
System Test Import Options Program Help	Version
Plans	-all-
Paskago Euross	Liuit No. Offecto
	1x1_No_Offsets
Testers	1x2_No_Offsets
Devices	2nd_Harmonic_Testing
Device Interfaces	40GHzTIMCheck
<u>F</u> ixtures	40GHz_Port1_ea_Cal
	40GHz_Port1_ea_Validate
	40GHz_Port1_Rcv_Freq_Resp_Cal
4	40GHz Port1 Rcv Freq Resp Validate
	select cancel new

### **Save and Title the Test Plan**

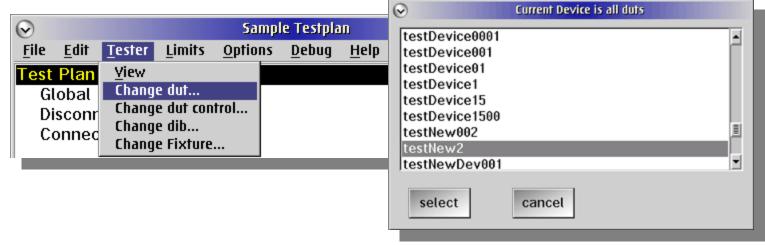
#### • File > Save Guru

$\odot$				N	o Title		800		
<u>F</u> ile	<u>E</u> dit	Tester	Limits	<u>O</u> ptions	<u>D</u> ebug	<u>H</u> elp			
		Setting				A	Compile		
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	sconi	nect Sei st Seque	ttings			=	Run		
	onneo	i sequ	ence				Repeat		
						$\odot$	Save Te	stplan	
						Type Demo Version 1.0.3 Status			
						alpha	•		
						Title New Title			-
						save	cancel		

#### **Selecting the Device Type**

#### • From Tester menu, Change dut

• Select the device



#### Repeat for all Tester resources (DUT, DUT control, DIB, and Fixture)

# Chapter Outline (Ch 3)

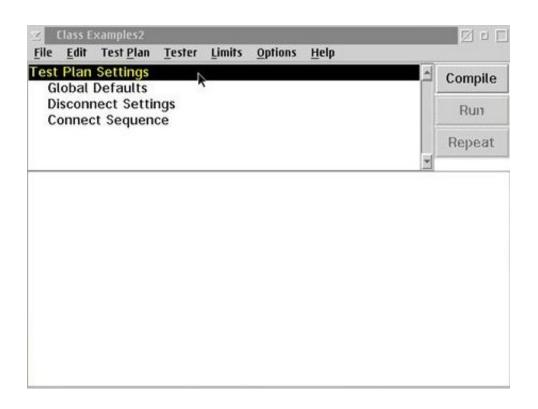
- Creating a New Test Plan
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## **Test Plan Structure**

- Global Defaults
- Disconnect Settings
- Connect Sequence
- Adding a Test Section
  - Conditional Statement
  - Section Defaults
  - Adding Test to a Test Section

### New Test Plan

Name of the test plan is displayed in the title barTest plan outline panel and setting panel

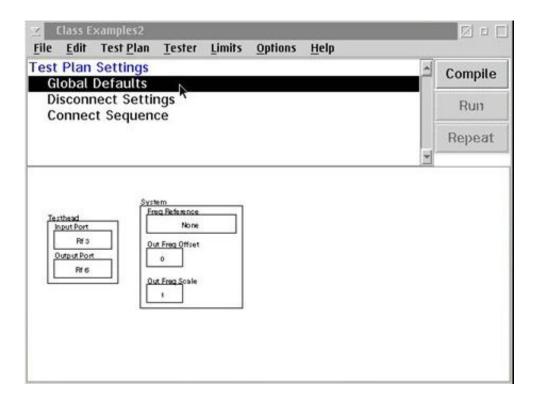


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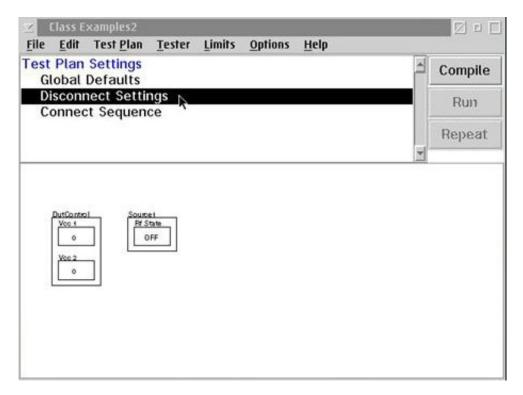
# **Global Defaults Panel**

• Global Defaults define the Test Plan's default settings for all of the instruments in the tester.



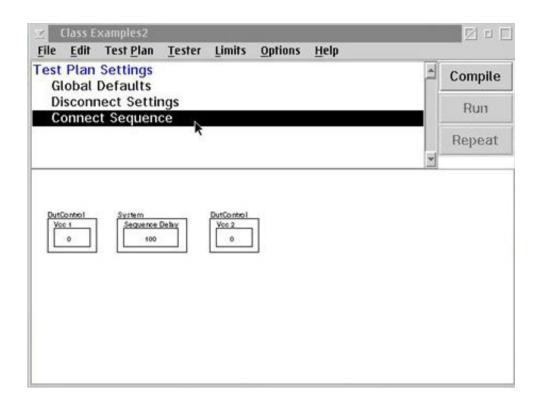
#### **Disconnect Settings Panel**

• Defines the specific state of the instruments at the moment the device-under-test is disconnected from the tester



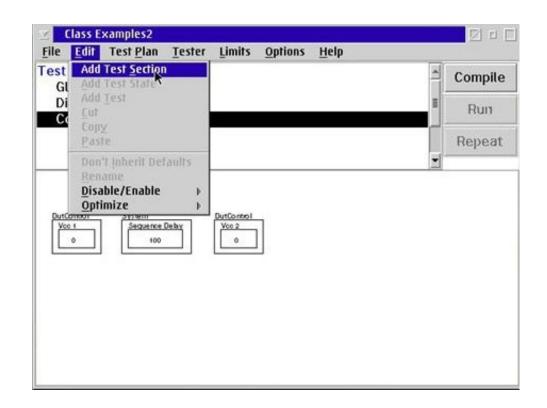
#### **Connect Sequence Panel**

Defines the order in which settings are activatedOrder of execution is from left to right



# Adding a Test Section

Each test plan must have at least one test section
Select menu Edit & Add Test Section



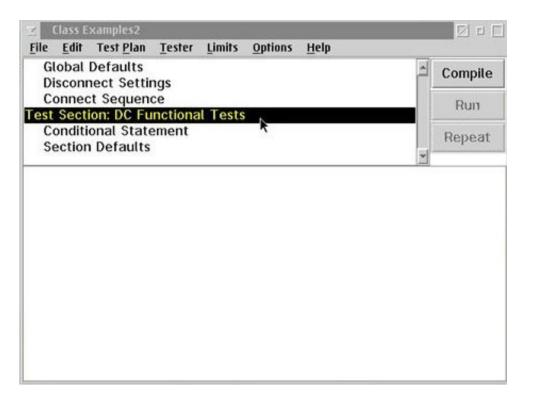


• Enter the title of the new test section.

	Title for New Test Section	1?
OC Funct	ional Tests	
01	Cancel	

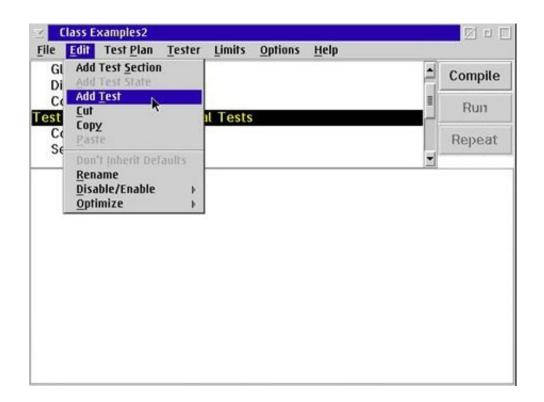
### **Test Section Layout**

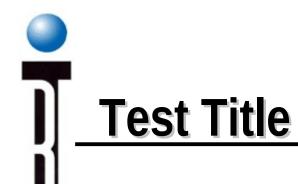
- Test Section Header
  - Conditional Statement
  - Section Defaults
  - One or more Test



#### Adding Test to a Test Section

- Select Test Section Header line in the test plan outline panel.
- Select menu Edit and Add Test.



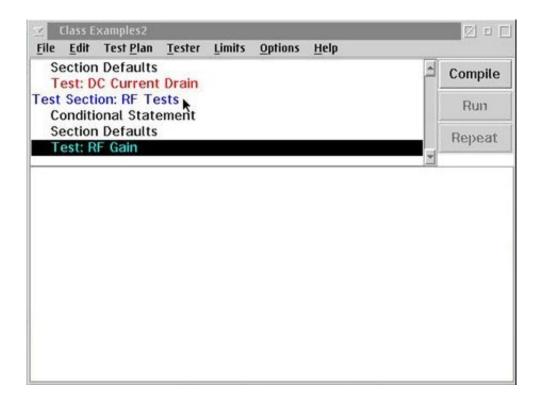


• Enter the title for the new test.

	Title for New Test?	
DC Curre	nt Drain	
	Cancel	

# **Additional Tests and Test Sections**

• Using the same procedure we have just describe



# Chapter Outline (Ch 3)

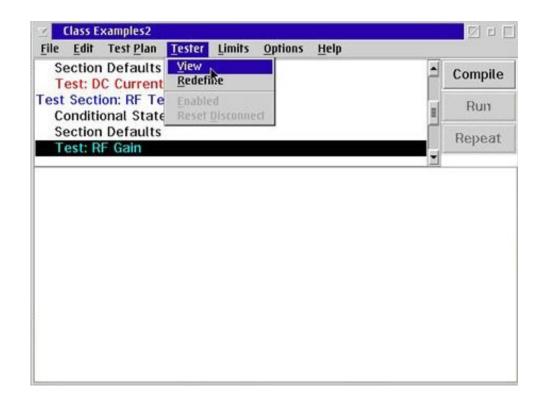
- Creating a New Test Plan
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#### **Building a Test**

- Open the Tester Viewer window
- "Select" to Copy the Desired Button
- Paste the Button into the Test Panel
- Organizing the Test Panel

#### **Open the Tester Viewer window**

• Select menu **Tester** and **View** 



## "Select" to Copy the Desired Button

- Select a instrument
- Select measurement or state
- RMBC (mouse button 2) on the button then click Select from the pop-up menu

D:\RIAPPS\tests	ys\Sys46_CF2 View	ver	
Src3Output  StaticDigital System Testhead Waveform	easurements	Measure the ling gain using a ful port corrected measurement	10000 C 1000
MEAS S Parameters A MEAS MEAS Show Note Edit Note Delete Group Selecte Settings Text	hase A tut VSWRA		
÷		4	NO.

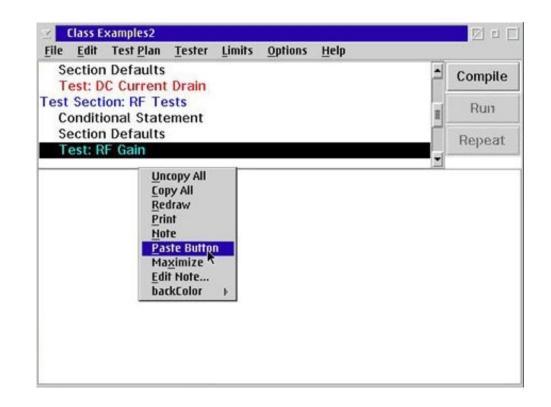
## **Selected Button is Highlighted**

• Tester Viewer window will indicate selected button by highlighting the button.

D:\RIAPPS	\testsys\Sys46_CF2 \	iewer 🛛 🖄 🗉 🗔
Src3Output StaticDigital System Testhead	measurements	Measure the linear gain using a full 2 port corrected measurement
vna		
Waveform	•	¥ ¥
S Parameter MEAS S11 A MEAS Cain A	MEAS Phase A MEAS Input VSWRA	

# Paste the Button into the Test Panel

Change the active window to the Test Plan Editor
RMBC (mouse button 2) on the desired location and select **Paste Button** from the pop-up menu.

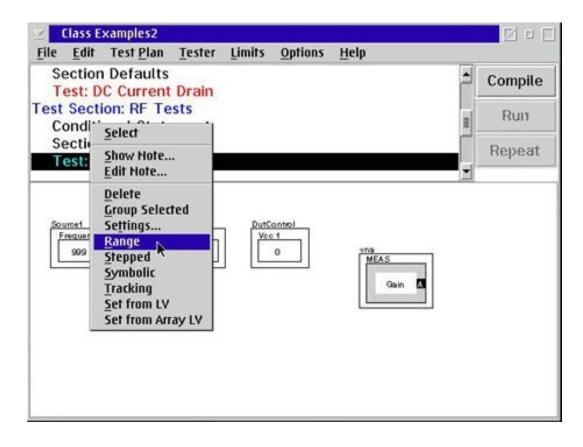


## **Organizing the Test Panel**

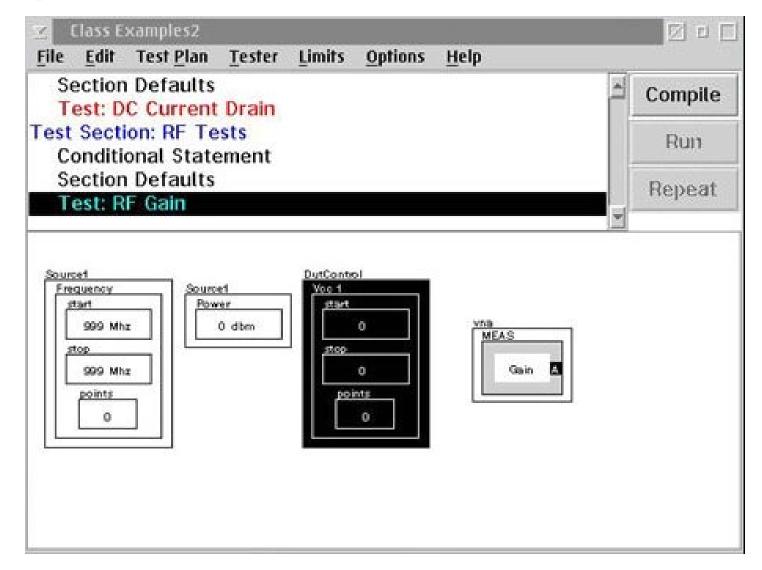
- RMBC (mouse button 2) and hold on the desired button then drag the button to new location
- Copying, Pasting, and Moving Buttons in the same process
- Short cut on copy button
   Ctrl + LMBC (mouse button 1)
- Short cut on paste button
   Ctrl + RMBC (mouse button 2)

# Changing from Single Value to Range

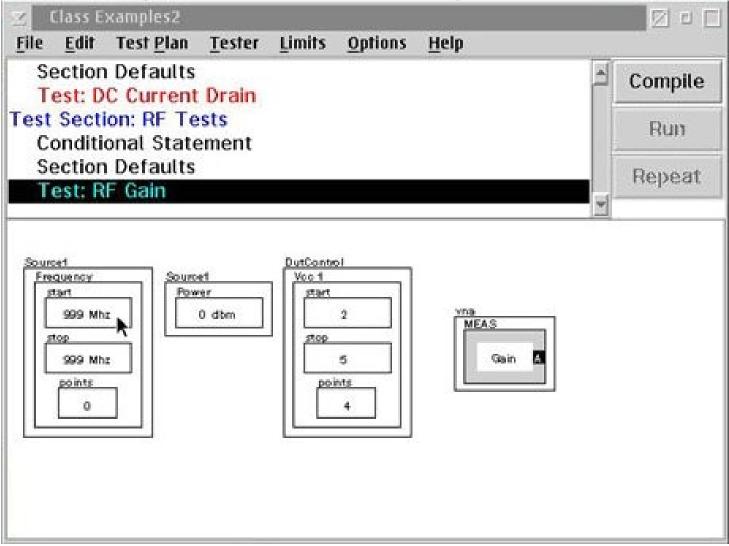
• Place the mouse pointer inside a state button, select pop-up menu Range



#### **Grouped Buttons**



### **Modifying Button Settings**

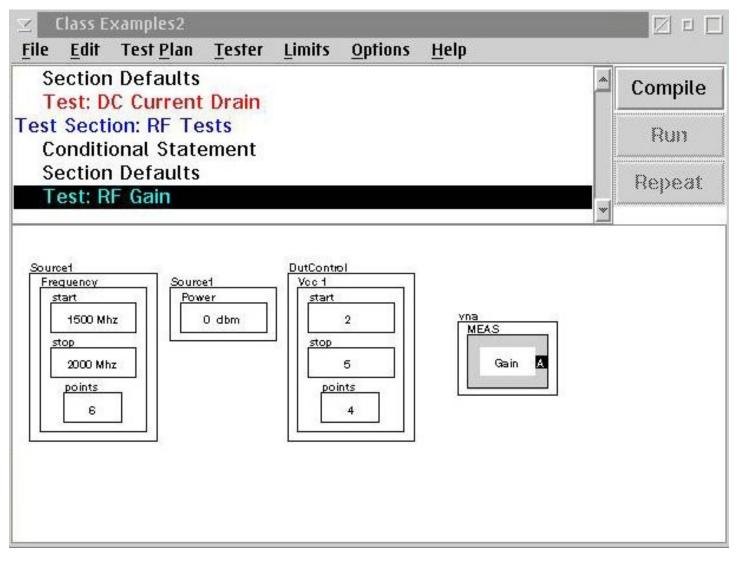


# Modifying Button Settings

• Type in the new value then click OK or press Enter

	Enter a Number	
1500		
OK .	Cancel	

#### **Test Example: RF Gain**

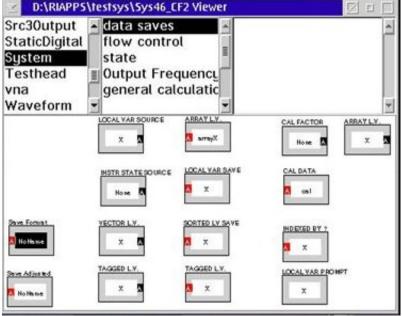


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## Saving Device Data

- Add the **SAVE DATA** buttons to the test panel
- Connect the MEAS button to the SAVE DATA button
- Each SAVE DATA button in the test plan must have a unique data name
   D1/RIAPPS1/restsys15ys46\_CF2 Viewer



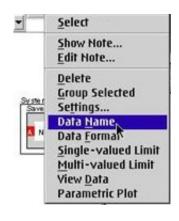
## Adding the SAVE DATA button

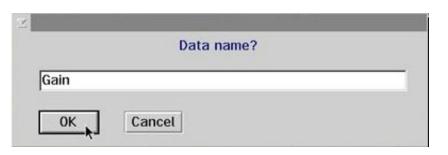
- Go to the Tester Viewer window.
- Select the **System** choice from the Instrument list.
- Select the **data saves** choice from the Button Type list.
- Select and copy one of the SAVE DATA buttons:
  - SAVE NO FORMAT
  - SAVE FORMAT
  - SAVE ADJUSTED
- Return to the Test Plan Editor and paste the Return to the Test Plan Editor and paste the **SAVE DATA** button button

# Data Name for the SAVE DATA button

### • RMBC on the SAVE DATA button

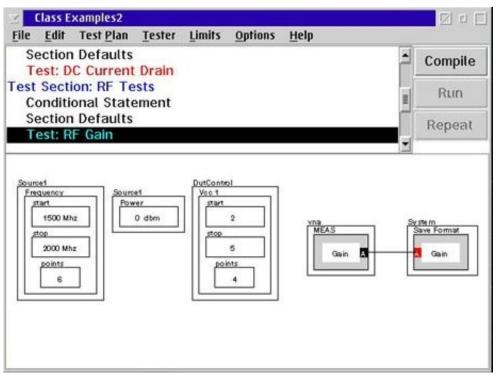
- Select Data Name
- Enter the desired **Data Name**





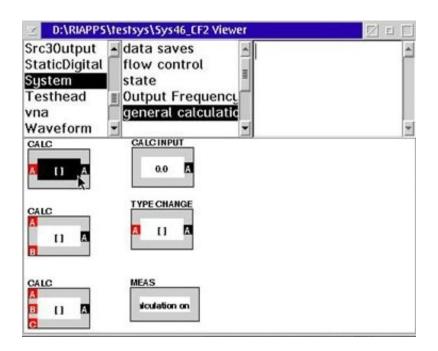
# Connecting MEAS & SAVE DATA buttons

- Press and hold RMB the **sending data port** of the MEAS button,
- Drag to the data receive port of SAVE DATA
- To disconnect the button repeat the process again.



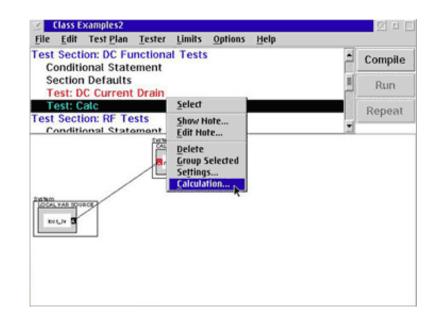


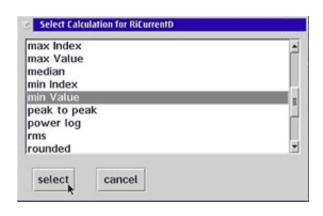
• Insert a general purpose CALC button and connect the lines as shown above.



### Setting the CALC button

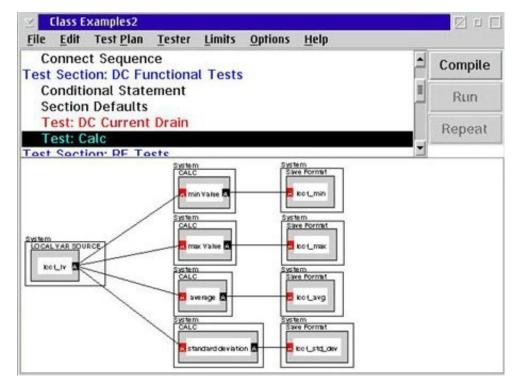
- RMBC and select **Calculation...**
- Select a calculation





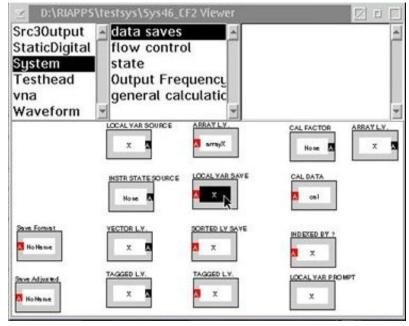
### **Saving Calibration Data**

- Connect the CALC button to the another CALC button, LOCAL VAR SOURCE, or SAVE FORMAT buttons
- A sending data port can connect to zero or more data receive port



# LOCAL VAR buttons

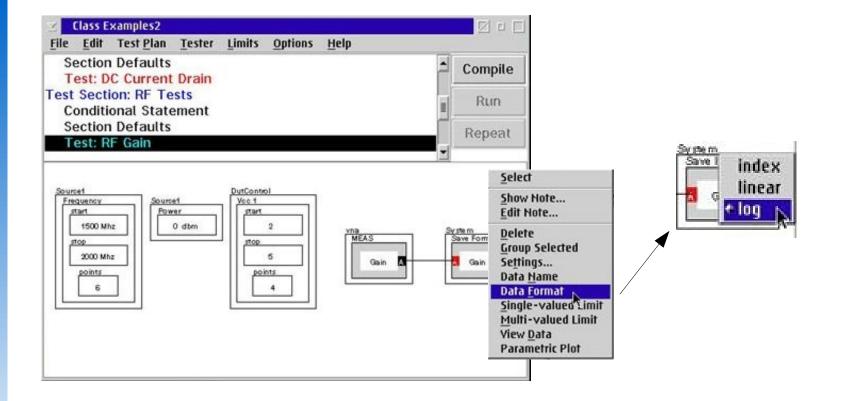
LOCAL VAR SAVE buttons
 LOCAL VAR SOURCE buttons
 Use a LOCAL VAR SAVE button with a LOCAL VAR SOURCE button to transfer test results from one test panel to another



### **Selecting the Data Format**

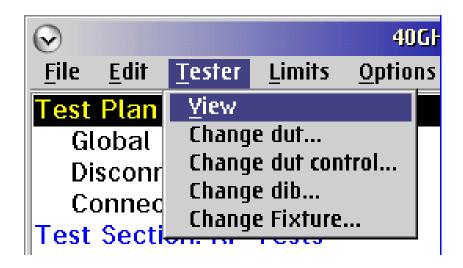
- Specify the data format (units) used by the system to save the data and limit check the data
- RMBC on SAVE Data button,
- select **Data Form** from the pop-up menu
- select one of format choice from the pop-up menu

### Data Format: Index, Linear, Log



## **Tester Configuration for the Test Plan**

- Physical Tester
- Loaded Tester
- View Tester Resources



# Chapter Outline (Ch 3)

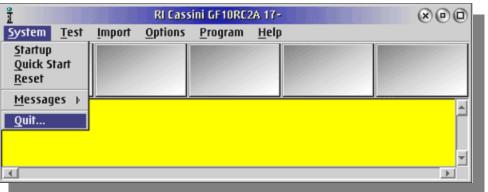
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# Tester System Mode

### • ACTIVE HARWARE MODE!!!!



#### • SIMULATION MODE!!!!

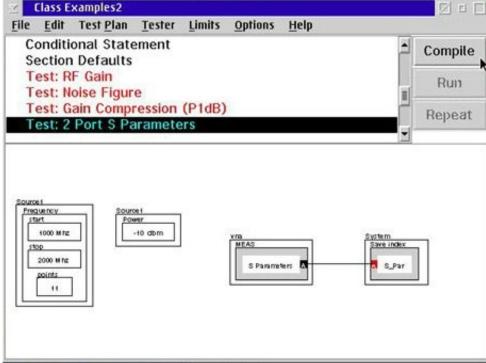


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# Compiling & Running Test Plan

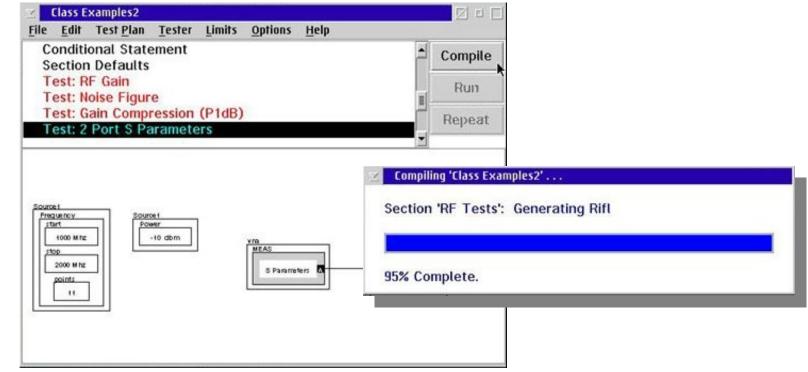
- Before a test plan can be executed, we need to compile and optimize it for the Tester
- Be sure that the current Active tester is the physical tester configuration



### **Compile and Optimize Test Plan**

• From the Test Plan Editor, select **Test Plan** menu & **Compile** 

### • Or the press **Compile** button on the top right





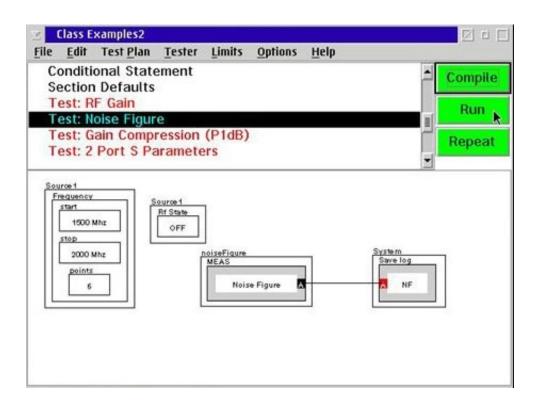
• If an error is discovered during the compile process

• Details are displayed in the RI Message Window



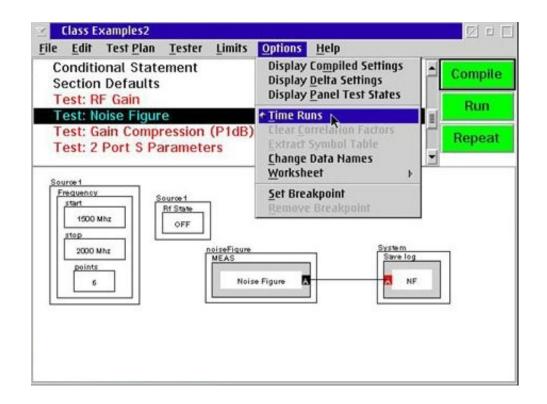
# Running a Test Plan

- Select Test Plan menu & Run
- or just press **Run** button on the top right



## Time Runs for a Test Plan

- To time how fast a Test Plan runs
- Select Options menu & Time Runs



# System Message window - Timing

• Detail timing display on the System Message window

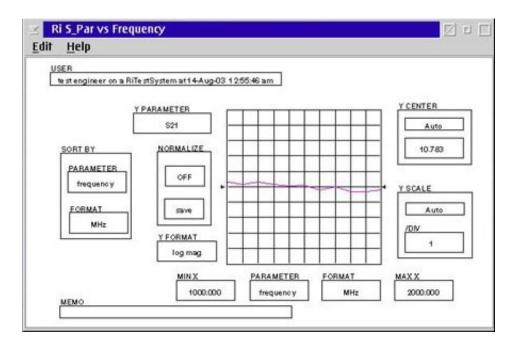
System I	est <u>O</u> ptions <u>H</u> elp	
918.982 m	s (mark run end) 59.591 ms	
978.573 m	s calc time for: 'RF Tests' 21.283 ms	- 11
999.856 m	s (mark calc end) 0.086 ms	- 1
999.942 m	s calc limits & statistics 0.427 ms	- 1
1000.369 r	ns (mark calc end) 0.072 ms	1
1000.441 r	ns End Timing.	

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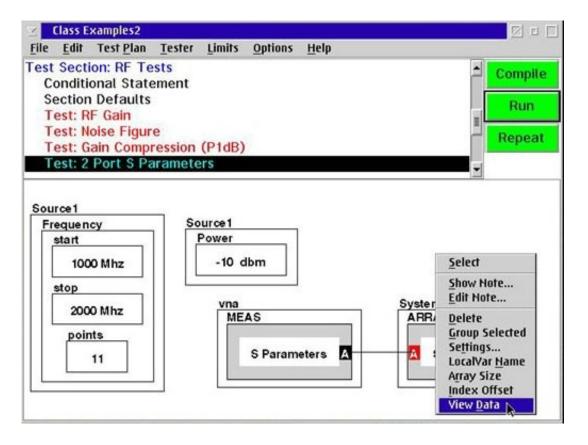
### Viewing Test Results

- Data Viewer displays the SAVE DATA button's Name and the name of the instrument settings button in its title bar
- Set the parameters, formats and order





# • RMBC on **SAVE DATA** button, select **View Data** from the pop-up menu



# Select Viewer Type

- Select a list of data viewer choices from the Select Viewer dialog box
- Rectangular
- Smith Chart
- Polar
- Strip Chart

Moving Strip Chart Polar Prec ADC Single on vs MeasureVForce	4
Rectangular Smith Chart	
Strip Chart	
Validation Plot	

# On Screen Help Text

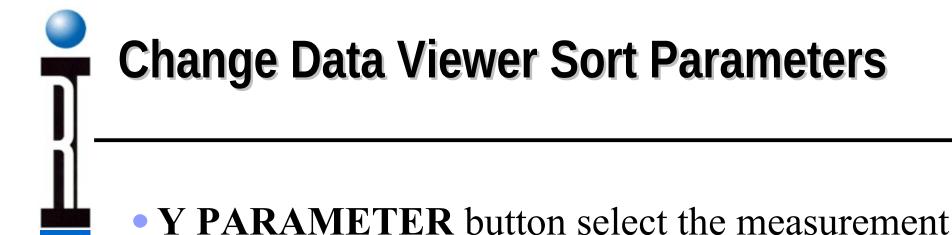
- RMBC on any of the button, select **Show Note...**
- For extensive on-screen reference information, click on **Help** menu

Help Index General Help Using Help Keys Help	14Aug-03 12	55:46 am		
Product Information				Auto
PARAMETER frequency FORMAT	OFF .			Y SCALE
	RMAT			/DN 1
	MIN X 1000.000	PARAMETER frequency	FORMAT MHz	MAX X 2000.000

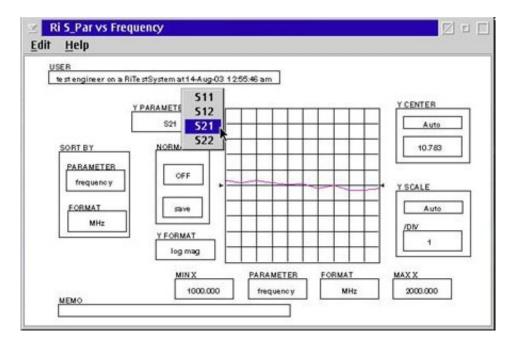
# Change Data Layout Format (SORT BY)

- **PARAMETER** button displays the parameter that the data is sorted by
- FORMAT button is used to displays the order of format in which the data is presented

SER		APR 40		
te st engineer on a RiTe stS	ystem at 14 Aug 03 12	200.46 am		
YPA				YCENTER
	\$21 -	++++		Auto
SORT BY	NORMALIZE			10.783
PARAMETER	OFF			
frequency				YSCALE
FORMAT index	59119			Auto
MH: MHZ	Y FORMAT			101/
	log mag			
	MINX	PARAMETER	FORMAT	MAXX
	1000.000	frequency	MHz	2000.000

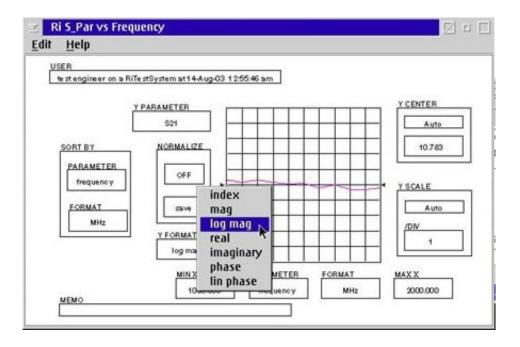


parameter data you want displayed along the Y axis



### **Change Data Viewer Format**

# • Y FORMAT button select the units and format of the Y Axis data.



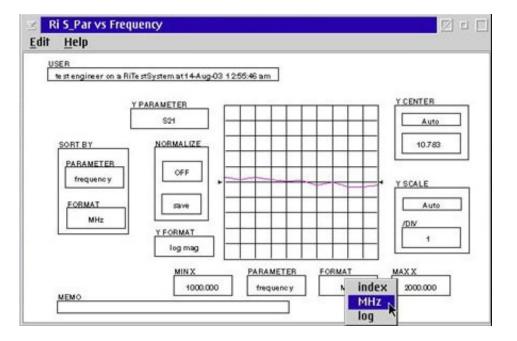


• Formats available depend on the measurement parameter selected

Ex. for the S21 measurement

### **Change Data Viewer Axis Scale**

# MIN X and MAX X FORMAT X axis Y CENTER and Y SCALE



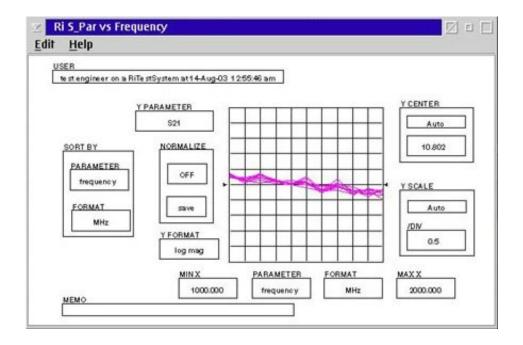
# **Change Data Viewer Normalization**

• NORMALIZE button enable you to save the test results currently displayed on the test results plot and to display succeeding test result traces relative to the test results data saved

SER	Te stSystem at 14 Aug-03 12	166.4C + ++		
testengineer on a Ki	resisystemat1+Aug-03 12	200.46 am		
				YCENTER
	\$21 -	++++		Auto
SORT BY	NORMALIZE			0.030793
PARAMETER frequency	ON			YSCALE
FORMAT	aw			Auto
MHz	YFORMAT			/DN
	log mag			1
	MINX	PARAMETER	FORMAT	MAXX

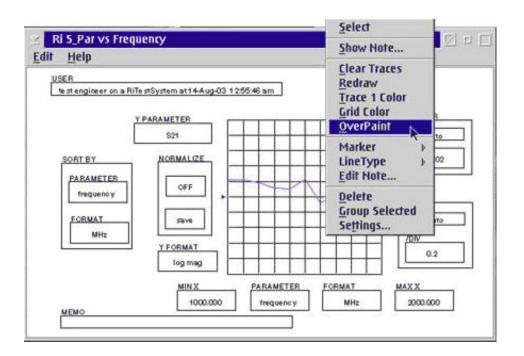
## **OverPaint Data Viewer Option**

• OverPaint is a toggle function



## **Using OverPaint Viewer Option**

• RMBC on the Data Viewer and select OverPaint from the pop-up menu



### **Adding Memo to Data Viewer**

- **MEMO** button provides capability to add text or comments to each plot
- Click on the **MENO** button and enter the text

JSER testengineer on a	RiTestSystem at 14 Aug-03 1255:46 am	
	Y PARAMETER	
	<u>\$21</u>	Auto
PARAMETER		10.802
frequency		
	Enter Text	-
Class Exa	nple2 for ZJL-7G	

# Use Data Viewer to Identify Data Point

# • LMBC on the Data Viewer identify the X and Y coordinates

SER								
test engineer on a n	iTe stSystem at 14 Aug	03 125	0:46 am					
	Y PARAMETER	X= 11	500 Y=	11.03				YCENTER
	\$21						_	Auto
							_	
SORT BY	NORMALIZE		_				_	10.802
PARAMETER			_				_	
frequency	OFF		-	2			-	YSCALE
			-	$\vdash$	T	1	_	
FORMAT	Save		+	$\square$	++	$\left  \right $	_	Auto
MHz	YFORMAT		-	$\vdash$	++	$\left  \right $	_	/DN
	log mag	1	-	$\vdash$	++	+++	_	0.5
								ter second
	MINX	_	PARA	METER	FO	RMAT	- 1	XXAX
	1000.00	00	freq	uency		MHz	11	2000.000



 Identify the difference between two point by click and hold on LMB on the first point then drag to the second point (delta X & delta Y coordinates)

ystem at 14 Aug-03	3 12:55:4	6am				
AMETER	deltaX	100 de	ita¥=-0/	45		YCENTER
S21	-	++				Auto
NORMALIZE						10.802
OFF	-	-	X		<u> </u>	YSCALE
save						Auto
YFORMAT	-				$\square$	
log mag					$\square$	0.5
MINX	F	ARAMET	TER	FORMA	т	MAXX
	S21 NORMALIZE OFF Save Y FORMAT log mag	S21 NORMALIZE OFF Save	S21 NORMALIZE OFF Save	S21 NORMALIZE OFF Save Y FORMAT log mag	S21 NORMALIZE OFF Save Y FORMAT log mag	S21 NOBMALIZE OFF Save Y FORMAT log mag

### Data Viewer Mouse Button 2 Functions

#### • RMBC on the Data Viewer

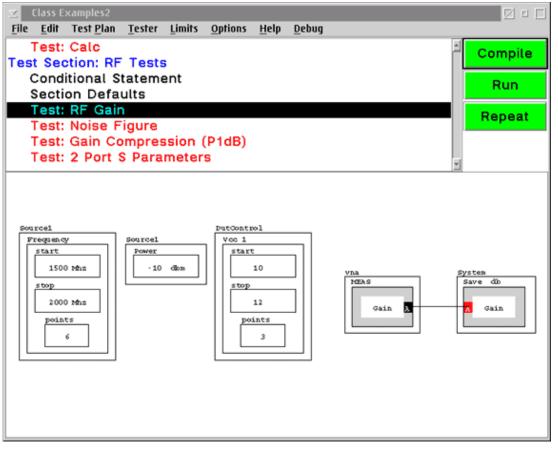
Clear Traces Redraw Trace 1 color Grid color Lines Marker Clear Max Min X select Line Type

Ri 5\_Par vs Frequency V I I Select Edit Help Show Note .... USER **Clear Traces** te st engineer on a RiTe stSystem at 14-Aug-03 12:55:46 am Redraw Trace 1 Color deitaX=100 deitaY=-0.45 Y PARAMETER **Grid Color** \$21 **OverPaint** NORMALIZE SORT BY Marker Clear LineType PARAMETER Max OFF Edit Note... Min frequency X select Delete FORMAT save **Group Selected** MHz Settings... Y FORMAT log mag PARAMETER MIN X FORMAT MAXX 1000.000 frequency MHz 2000.000 MEMO Class Example2 for ZJL-7G

### **Multi-Dimentional Data Viewers**

• Multi-Dimensional Data Viwer uses different colored traces to distinguish between different

parameter values



# Opening a Multi-Dimentional Data Viewer

- RMBC on SAVE DATA button, select the **View Data** option
- Select parameter for the X axis
- Select parameter to display different colored trace lines

nuependent v	ariables		
X Axis		Colors	
DutControl V Source1 Fre		DutControl Vcc1	A V
,		,	
ixed Variables			
/ariable:		Value:	
	-		1
	×		¥

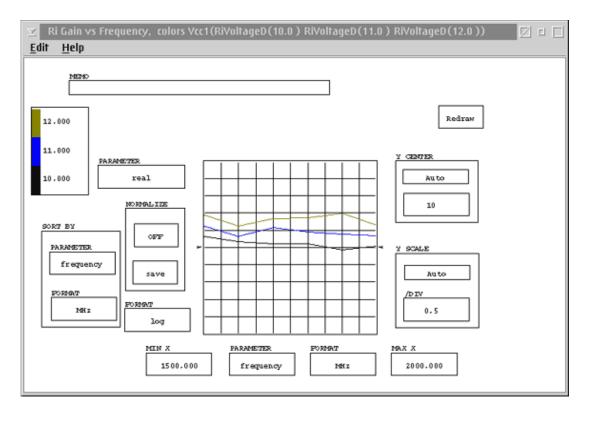


• Select a viewer from the Select Viewer dialog box

Select Viewer	
Mattiparameter	-
Multiparameter Polar	
1	1
Select Cancel	

# Using the Multi-Dimensional Data Viewer

 Multi-Dimensional Data Viewer similar to the X & Y coordinate data viewer with added buttons color bar and Redraw

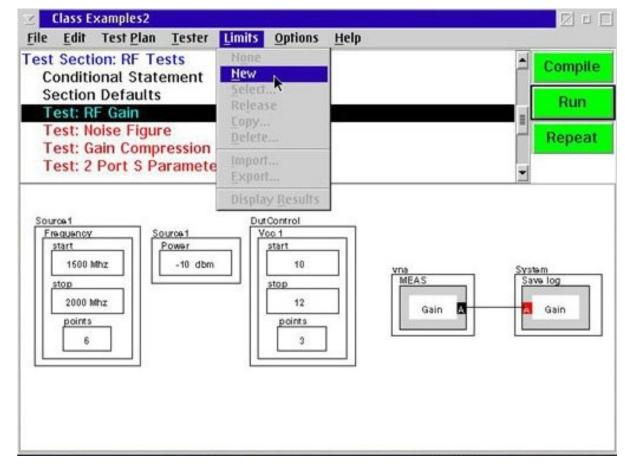


### **Setting and Selecting Limits**

- Each test plan can have one or more sets of test limits associated with the test plan.
- Need compiled and run the test plan at least once before creating test limits
- To set test limits to the test plan, you must first either open an existing set of test limits or create a new set of test limits.

### **Create new set of test limits**

### Select the Test Plan Editors menu Limits and New



### <u>Histogram</u>

• Enter a title for the new test limits and click OK

• Reserved name Histogram

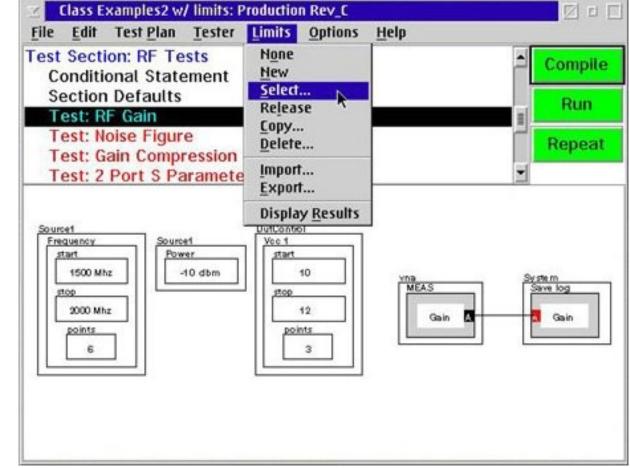
	Title?	
Productio	on Rev_C	
OK	Cancel	

## Chapter Outline (Ch 3)

- Creating a New Test Plan
- Understanding Test Plan Structure
- Building a Test Plan
- Saving Data
- Editing the Tester Configuration
- Compiling & Running Test Plan
- Viewing Test Results
- Setting Limits
- Release Test Plan for Production

### **Selecting Test Limits**

# • Select the Test Plan Editors menu Limits and Select...



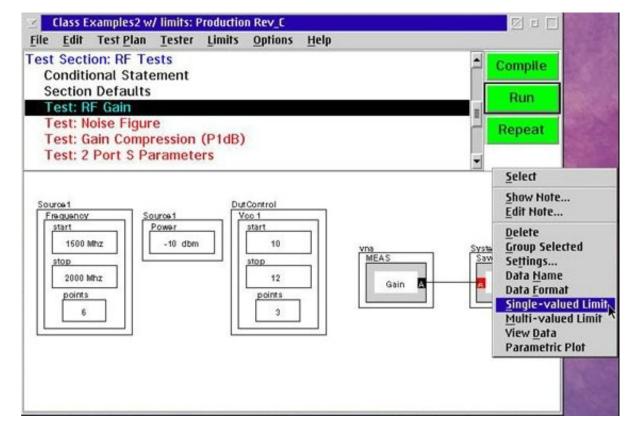
# Test Limits

- Test Plan Editor displays the Select Test Limits dialog box
- Select the desired test limits

istogram roduction Re	ev_C	i i i i i i i i i i i i i i i i i i i
		*

## Adding Single Valued Test Limits

- RMBC on the DATA SAVE button
- Select the Single-valued Limit from pop-up menu



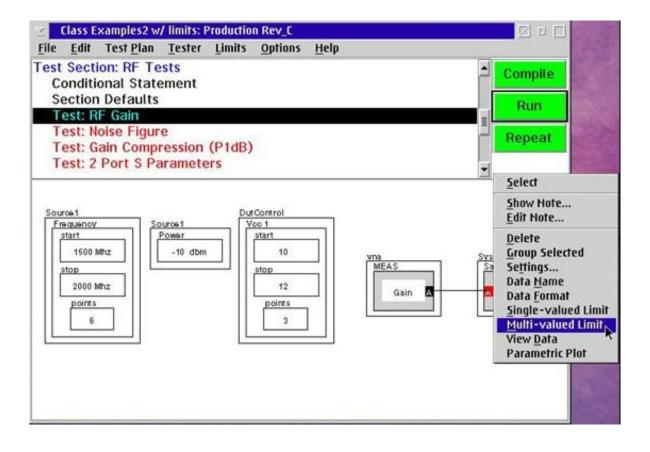
# Test Limit Types

- Test Plan Editor will display the **Set Test Limits** dialog box
- Enter the upper and/or lower limit
- Select the **OK** button

Data Format	:: log
Minimum: [1	0.0
Maximum:	
Ok .	Cancel

### **Adding Multi-Valued Test Limits**

- RMBC on the DATA SAVE button
- Select the Multi-Valued Limit from pop-up menu



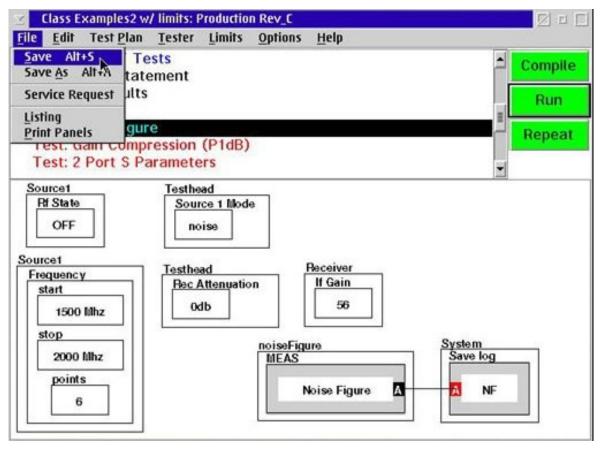
# Upper or Lower Limits

• Enter the upper and/or lower limits for each of the point

ettings	
Vcc1, Frequency 11.0, 1800.0 11.0, 1900.0 11.0, 2000.0 12.0, 1500.0 12.0, 1600.0 12.0, 1700.0 12.0, 1800.0 12.0, 1900.0 12.0, 2000.0	Minimum: [1θ.θ] Maximum:

# Saving the Test Limit

- Save the test limits with the test plan
- Test Plan Editors menu File and Save



## Chapter Outline (Ch 3)

- Creating a New Test Plan
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### Release Test Plan for Production

# **Release for Production**

• Change status to released

$\odot$	Save Testplan
Туре	
Demo 🔹	
Version	
3 🔹	
Status	
released -	
alpha 🔺	
beta	
released 💌	
save	1

## Chapter Outline (Ch 3)

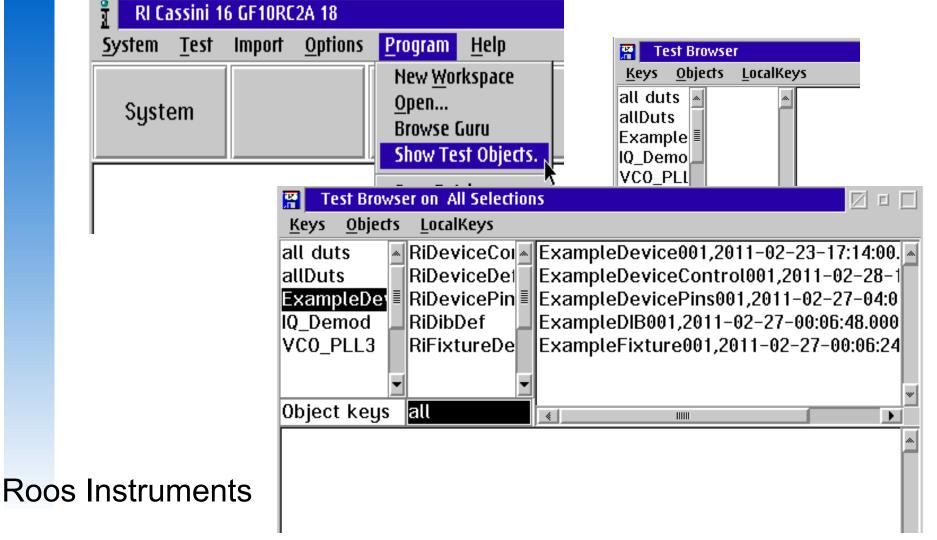
- Creating a New Test Plan
- Editing the Tester Configuration
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. . .

- Release Test Plan for Production
- Opening a Previous Version (Guru)
- Package Exec: Handler Bin Definitions
   Roos Instruments

### **Opening a Previous Version**

### Show Test Objects navigation window



## Chapter Outline (Ch 3)

- Creating a New Test Plan
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### Package Exec: Handler Bin Definitions

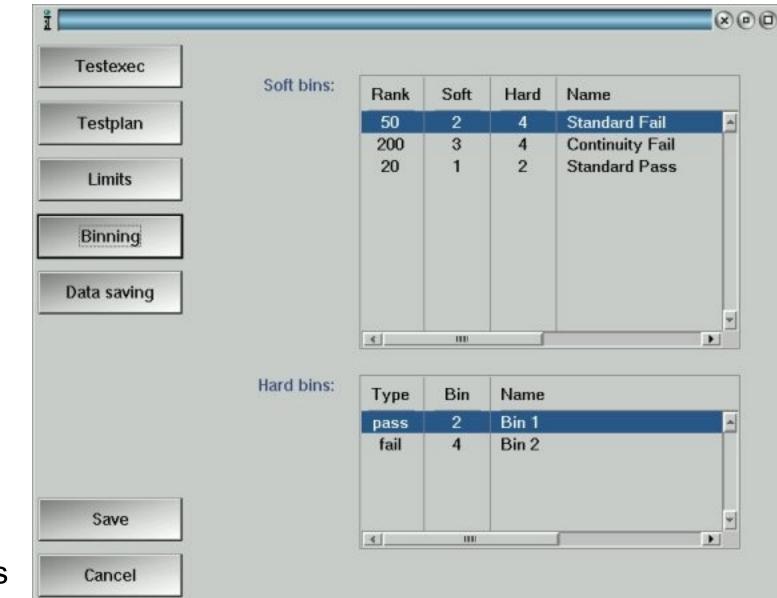
Roos Instruments

. . .

### Package Exec: Handler Bins

- Choose "hard" or "soft" bin for each category
- Hard bin is the sort value sent to the handler
- Soft bin is stored in data logs (STDF)
- If using Retset Criteria, you should use a "replunge" capable hander
- Set the "retset bin" signal to cause a handler replunge

### Package Exec: Handler Bins



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. . .

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### Chapter Review (Ch 3)

- Creating a New Test Plan
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- Building a Test Plan
- Saving Data
- Editing the Tester Configuration
- Compiling & Running Test Plan
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- Setting Limits
- Release Test Plan for Production



- Science of RF Measurement
- Device Definitions
- Example Application Development
- Fixture ad Device Interface Design
- Test Design & Best Practices

### Questions?



### Any Questions from this Chapter?